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Form PTO 1449	U.S. DEPARTMENT OF COMMERCE			ATTY DOCKET NO.	SERIAL NO.				
(Modified)		PATENT AND TRAD	EMARK OFFICE	245902US2	10/723,603				
				APPLICANT					
LIST OF	REFER	RENCES CITED BY API	PLICANT	Ayako KOBAYASHI					
				FILING DATE	GROUP				
			November 26, 2003	2625					
				U.S. PATENT DOCUMENTS					
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB FILING DATE CLASS IF APPROPRIATE			
/A.N./	AA	US 6,338,080 B1	01/08/2002	Daniel Lucien DURAND, et al.					
/A.N./	AB	US 2002/0184499A1	12/05/2002	Toshihiro TAGUCHI, et al.					
/A.N./	AC	US 6,177,957 B1	01/23/2001	Eric ANDERSON					
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		DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION YES NO		NO	
/A.N./	AO	JP 11-161504	06/18/1999	Japan (corresponding to US 6,338,080	B1)	<u> </u>		×	
	AP	JP 2000-10786	01/14/2000	Japan (with English abstract)				x	
	AQ	JP 2002-318692	10/31/2002	Japan (corresponding to US 2002/0184	499 A1)	<u> </u>		×	
	AR	JP 2002-505492	02/19/2002	Japan (corresponding to US 6,177,957	B1)			×	
V	AS	JP 9-152972	06/10/1997	Japan (with English abstract)				X	
	AT								
	AU								
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		OTHER R	EFERENCES	(Including Author, Title, Date, Pertinen	t Pages, e	etc.)			
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	AY								
	AZ					Additional References sheet(s) attached			
Examiner /Allen Nguyen/					Date Considered 02/02/2009				
*Examiner: I	nitial if	reference is considered	, whether or no	ot citation is in conformance with MPEP 6 m with next communication to applicant.	09; Draw	ine through	h citation	ıf not in	
Comonnance	onu II	or considered, include t	opy or une lon	applicant.					